

Device Modeling Report

COMPONENTS: MOSFET (Professional Model)
PART NUMBER: 2SK4063LS
MANUFACTURER: SANYO
REMARK: Body Diode (Professional Model)



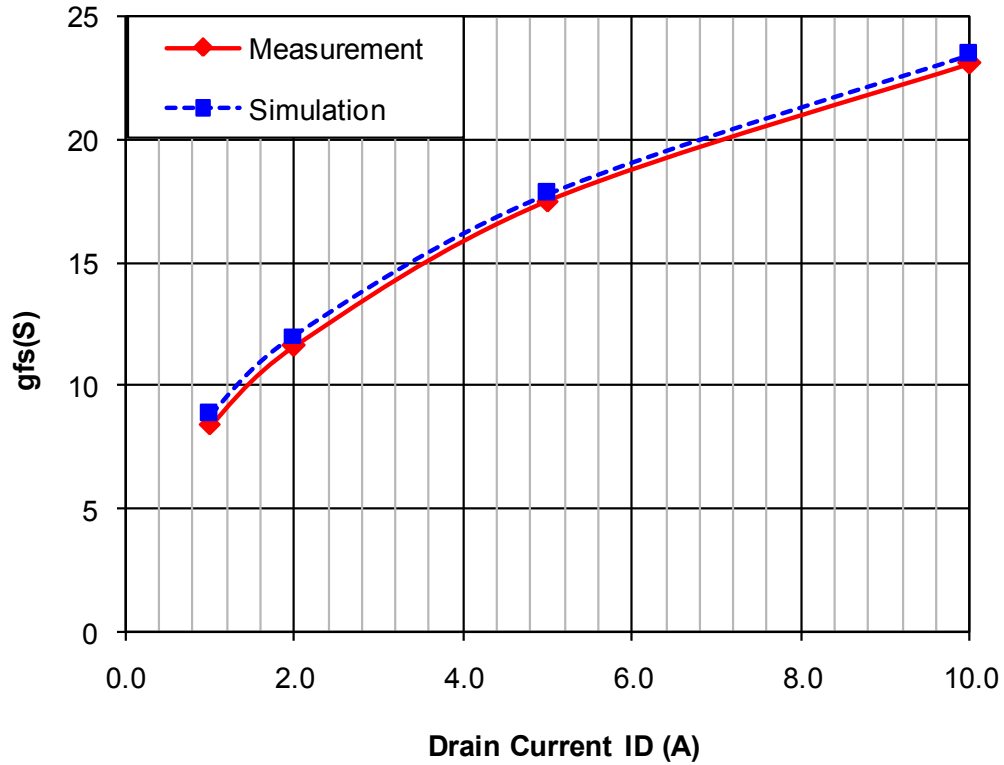
Bee Technologies Inc.

MOSFET MODEL

PSpice model parameter	Model description
LEVEL	
L	Channel Length
W	Channel Width
KP	Transconductance
RS	Source Ohmic Resistance
RD	Ohmic Drain Resistance
VTO	Zero-bias Threshold Voltage
RDS	Drain-Source Shunt Resistance
TOX	Gate Oxide Thickness
CGSO	Zero-bias Gate-Source Capacitance
CGDO	Zero-bias Gate-Drain Capacitance
CBD	Zero-bias Bulk-Drain Junction Capacitance
MJ	Bulk Junction Grading Coefficient
PB	Bulk Junction Potential
FC	Bulk Junction Forward-bias Capacitance Coefficient
RG	Gate Ohmic Resistance
IS	Bulk Junction Saturation Current
N	Bulk Junction Emission Coefficient
RB	Bulk Series Resistance
PHI	Surface Inversion Potential
GAMMA	Body-effect Parameter
DELTA	Width effect on Threshold Voltage
ETA	Static Feedback on Threshold Voltage
THETA	Mobility Modulation
KAPPA	Saturation Field Factor
VMAX	Maximum Drift Velocity of Carriers
XJ	Metallurgical Junction Depth
UO	Surface Mobility

Transconductance Characteristic

Circuit Simulation Result

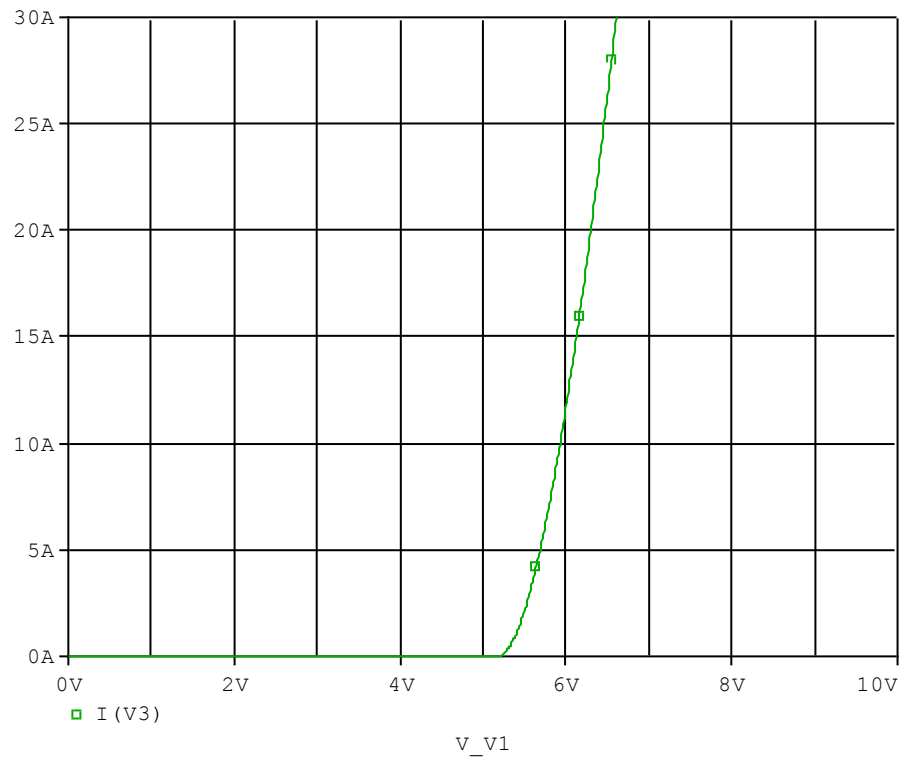


Comparison table

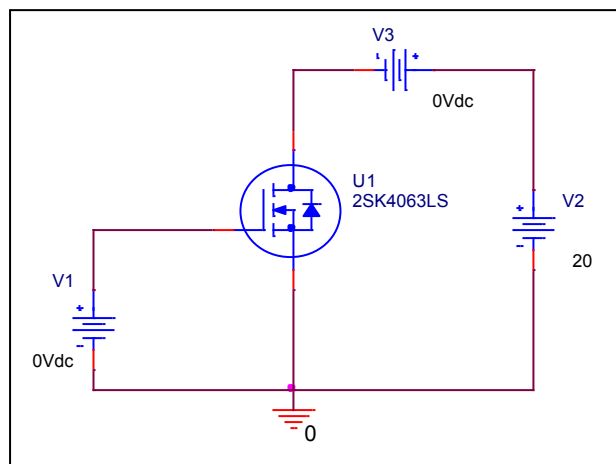
Id(A)	gfs(S)		Error (%)
	Measurement	Simulation	
1	8.400	8.818	4.98
2	11.600	12.035	3.75
5	17.500	17.788	1.65
10	23.100	23.431	1.43

V_{gs}-I_d Characteristic

Circuit Simulation result

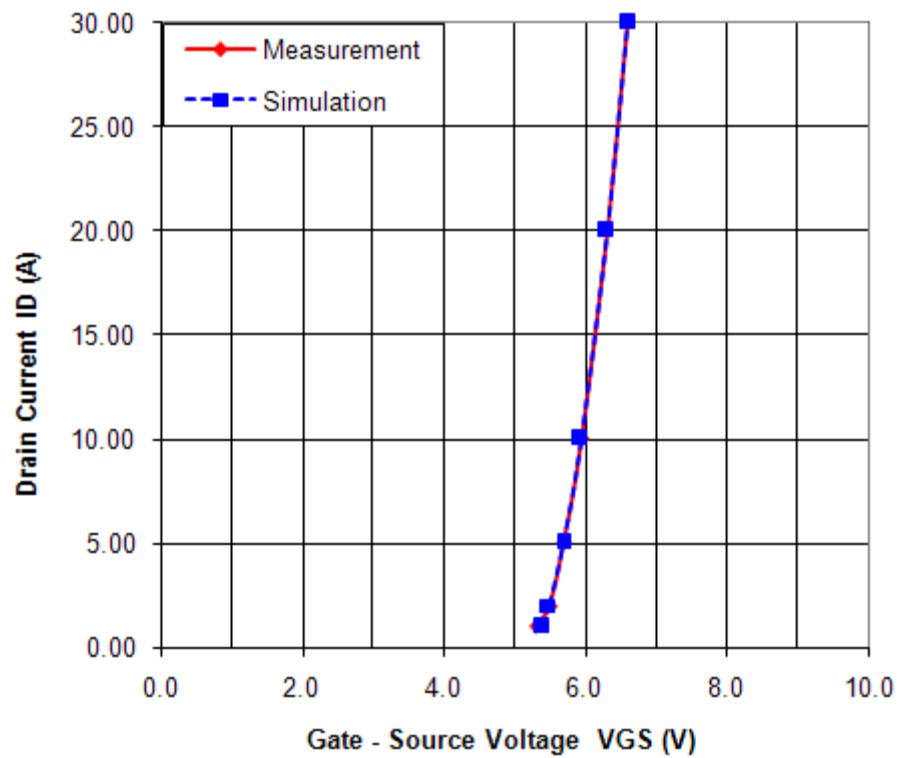


Evaluation circuit



Comparison Graph

Circuit Simulation Result

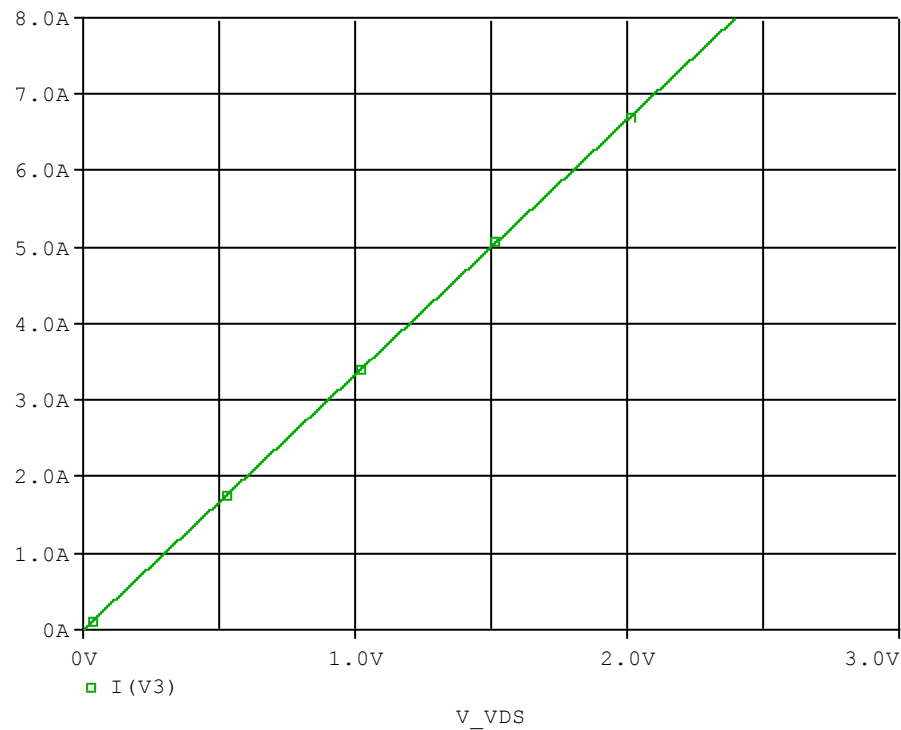


Simulation Result

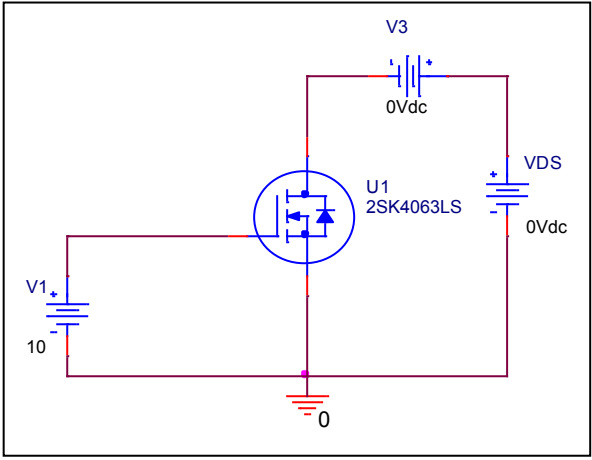
I_D (A)	V_{GS} (V)		Error (%)
	Measurement	Simulation	
1	5.300	5.394	1.77
2	5.500	5.490	-0.19
5	5.700	5.689	-0.19
10	5.950	5.931	-0.32
20	6.300	6.302	0.02
30	6.600	6.609	0.14

Rds(on) Characteristic

Circuit Simulation result



Evaluation circuit

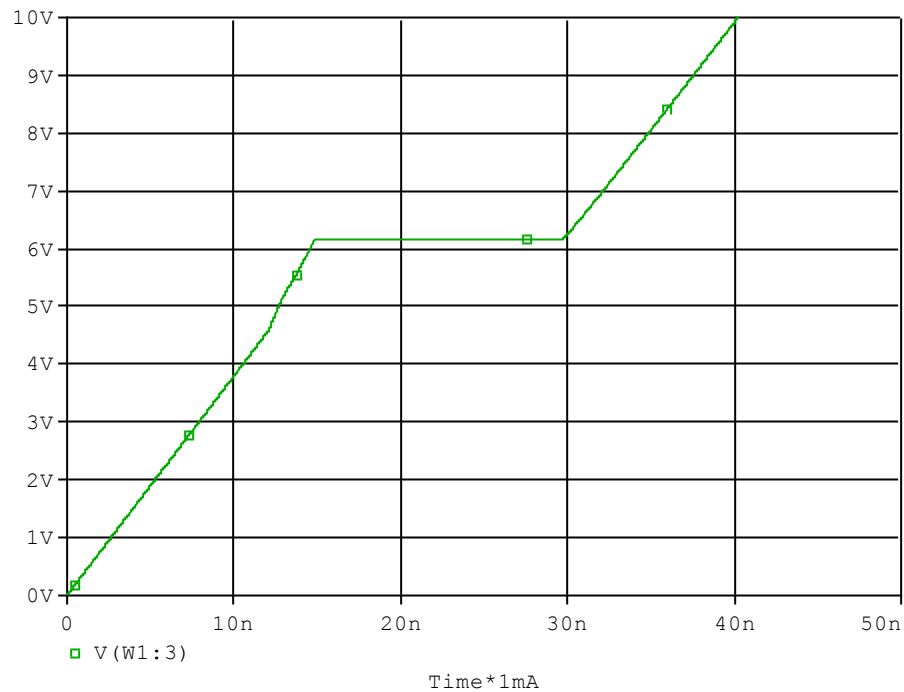


Simulation Result

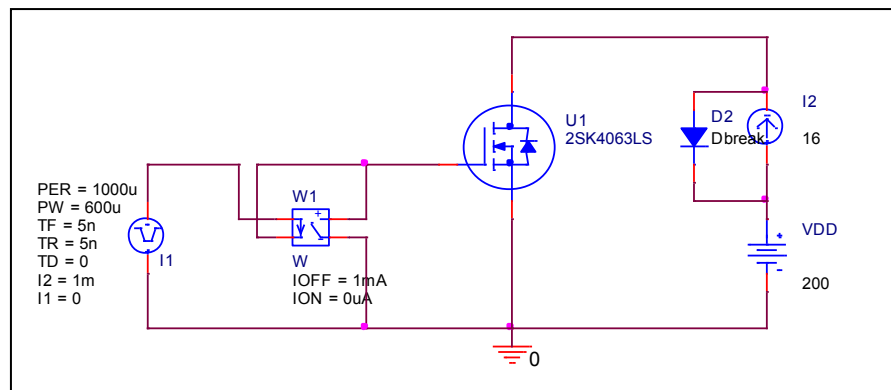
I _D = 8A, V _{GS} = 15V		Measurement	Simulation	Error (%)
R _{DS} (on)	Ω	0.300	0.300	0.00

Gate Charge Characteristic

Circuit Simulation result



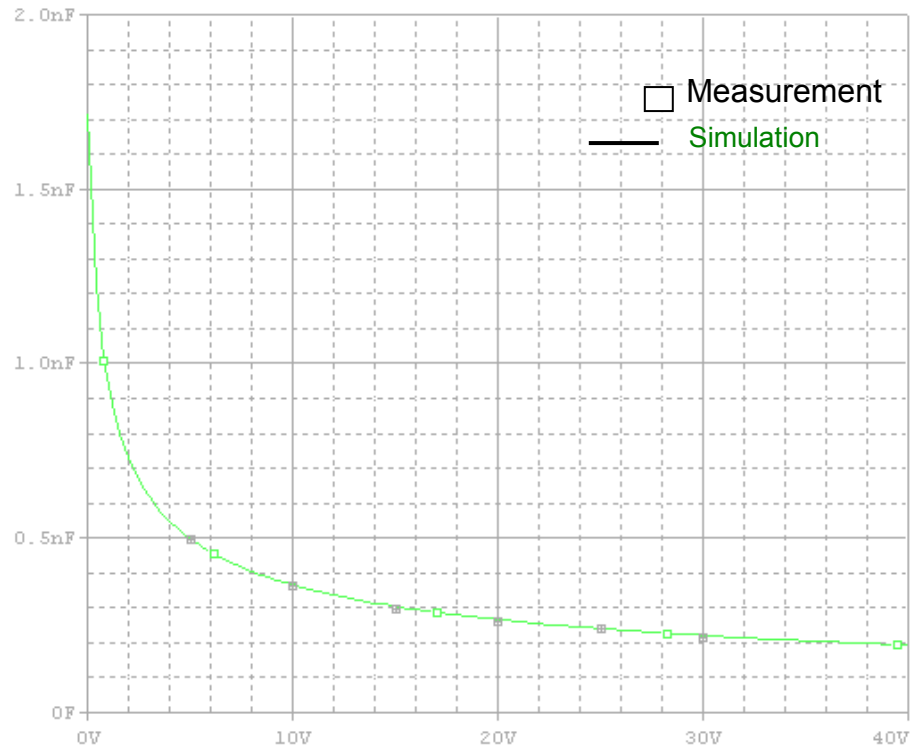
Evaluation circuit



Simulation Result

$V_{DD}=200V, I_D=16A,$ $V_{GS}=10V$		Measurement	Simulation	Error (%)
Qgs	nC	15.200	14.870	-2.17
Qgd	nC	15.200	14.841	-2.36
Qg	nC	40.000	40.236	0.59

Capacitance Characteristic

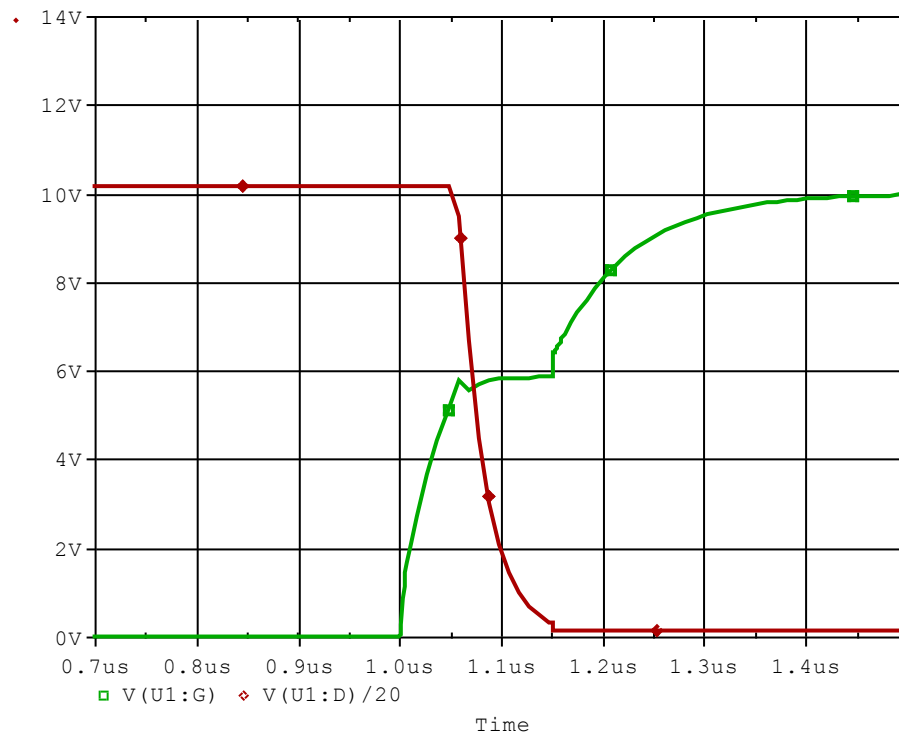


Simulation Result

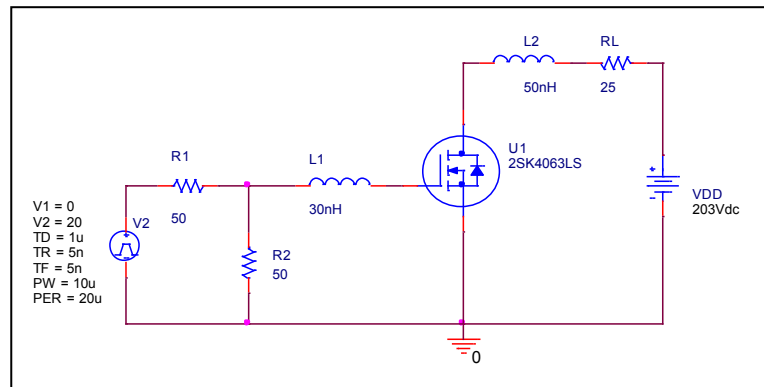
V_{DS} (V)	Cbd (pF)		Error (%)
	Measurement	Simulation	
5.000	499.000	498.600	-0.08
10.000	367.000	366.250	-0.20
15.000	300.000	304.490	1.50
20.000	268.000	266.775	-0.46
25.000	244.000	240.643	-1.38
30.000	220.000	221.143	0.52

Switching Time Characteristic

Circuit Simulation result



Evaluation circuit

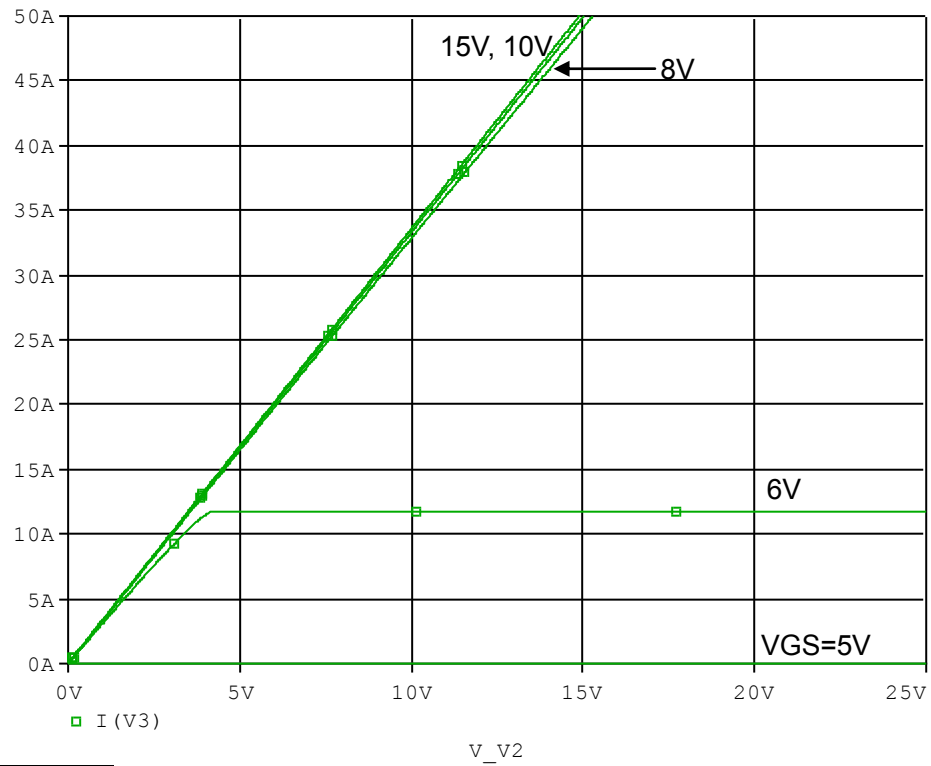


Simulation Result

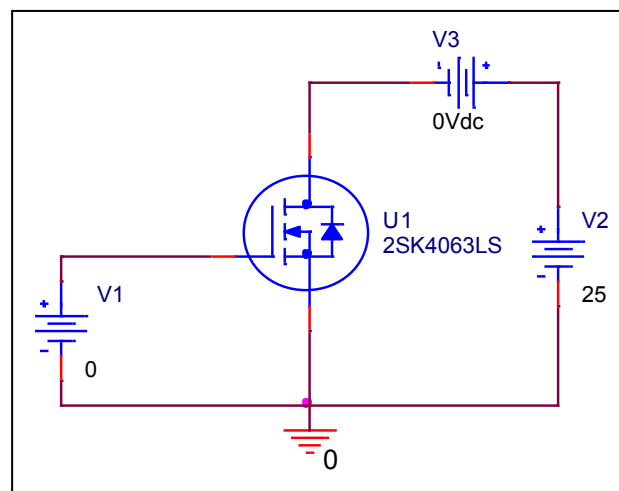
$I_D=8A$, $V_{DD}=200V$ $V_{GS}=0/10V$		Measurement	Simulation	Error(%)
t_{don}	ns	55.000	54.992	-0.01

Output Characteristic

Circuit Simulation result

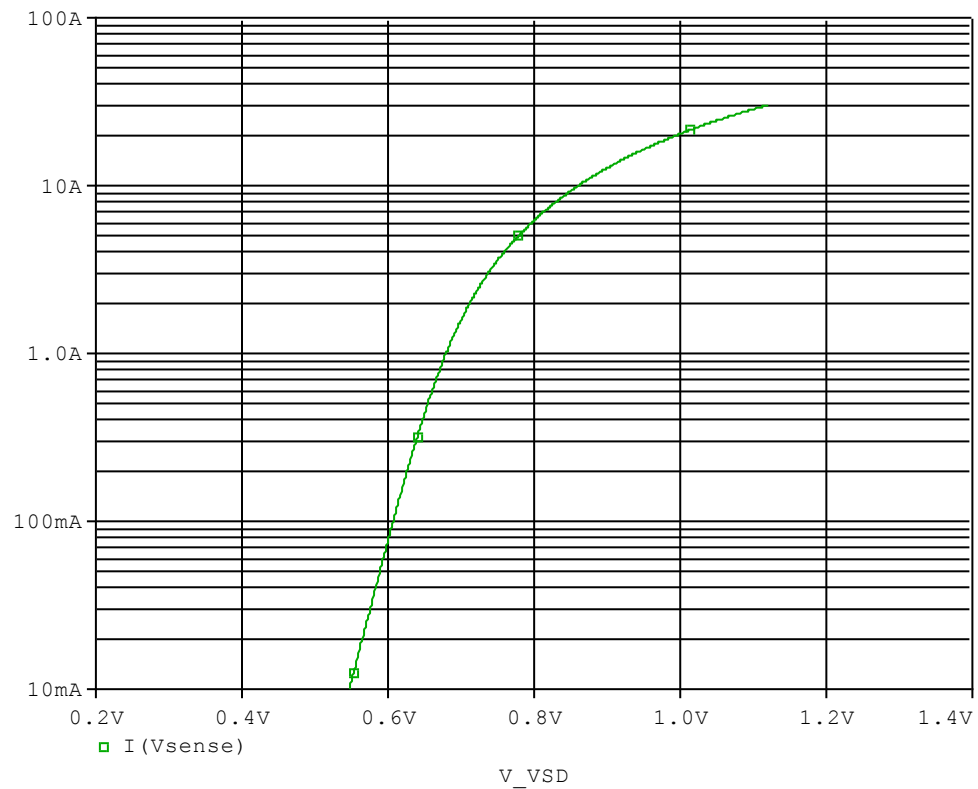


Evaluation circuit

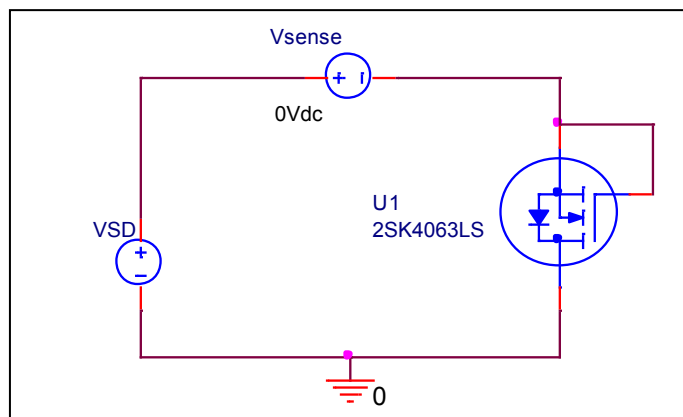


Forward Current Characteristic

Circuit Simulation Result

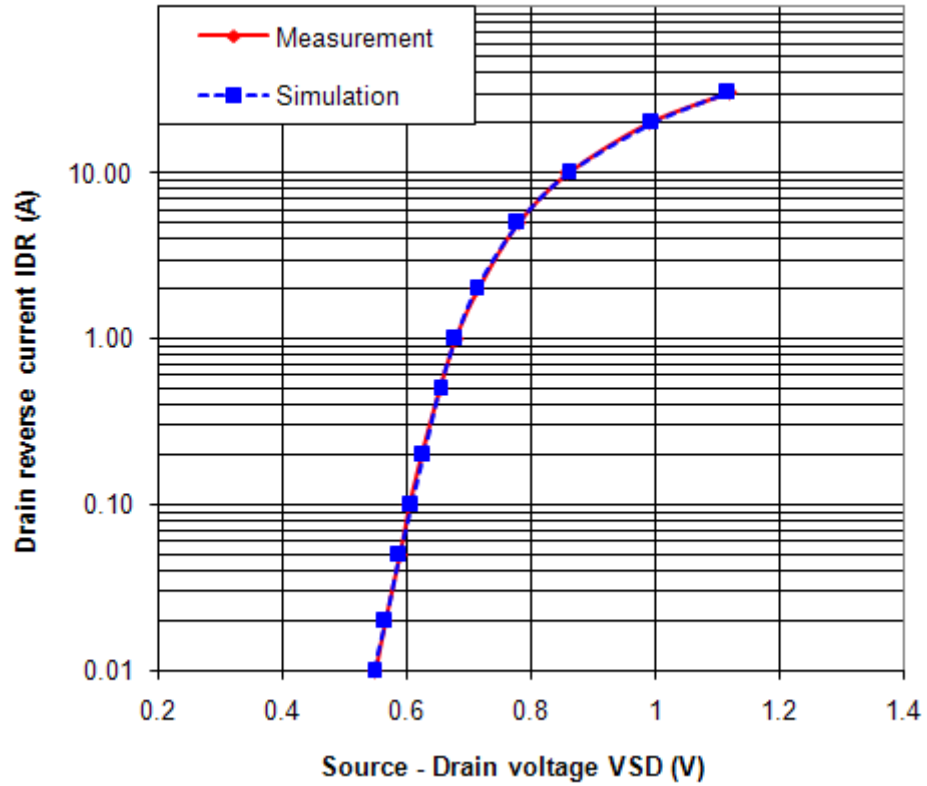


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

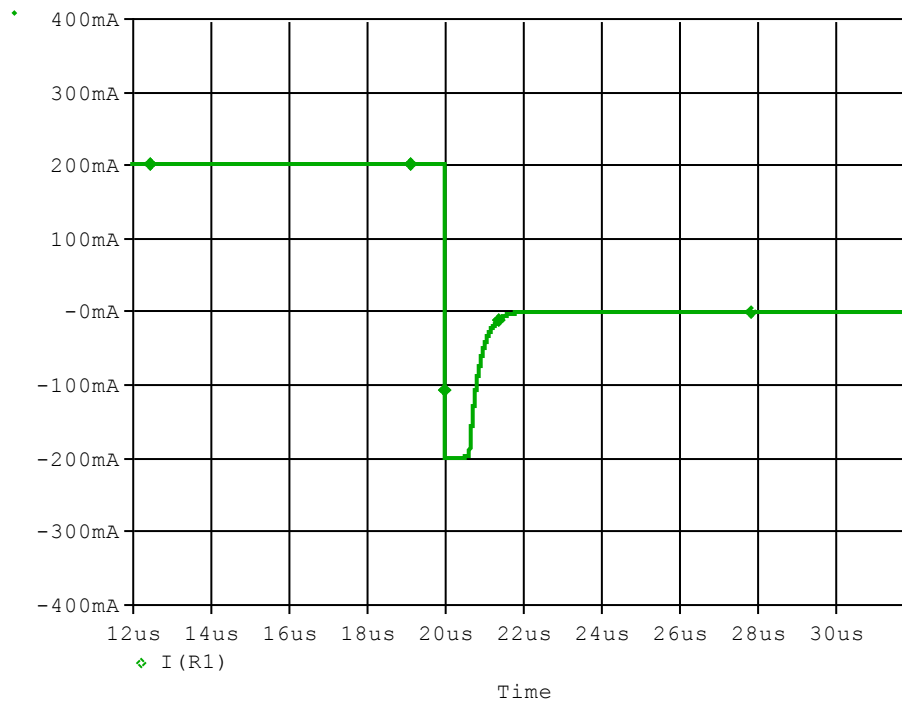


Simulation Result

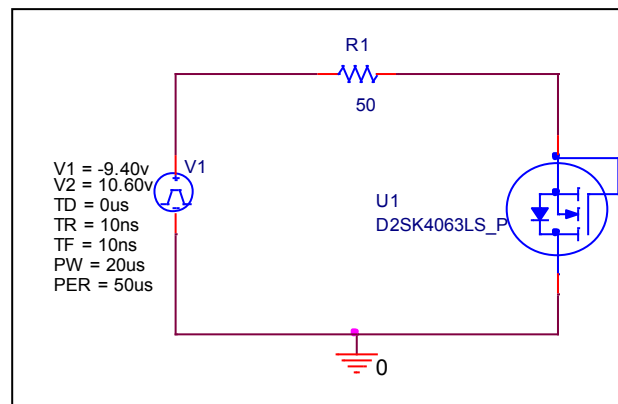
IDR(A)	VSD(V)		%Error
	Measurement	Simulation	
0.01	0.5500	0.5471	-0.53
0.02	0.5650	0.5649	-0.03
0.05	0.5900	0.5886	-0.23
0.1	0.6050	0.6071	0.34
0.2	0.6250	0.6262	0.20
0.5	0.6550	0.6541	-0.13
1	0.6800	0.6794	-0.09
2	0.7150	0.7120	-0.41
5	0.7800	0.7782	-0.22
10	0.8600	0.8607	0.08
20	0.9900	0.9958	0.59
30	1.1200	1.1170	-0.27

Reverse Recovery Characteristics

Circuit Simulation Result



Evaluation Circuit

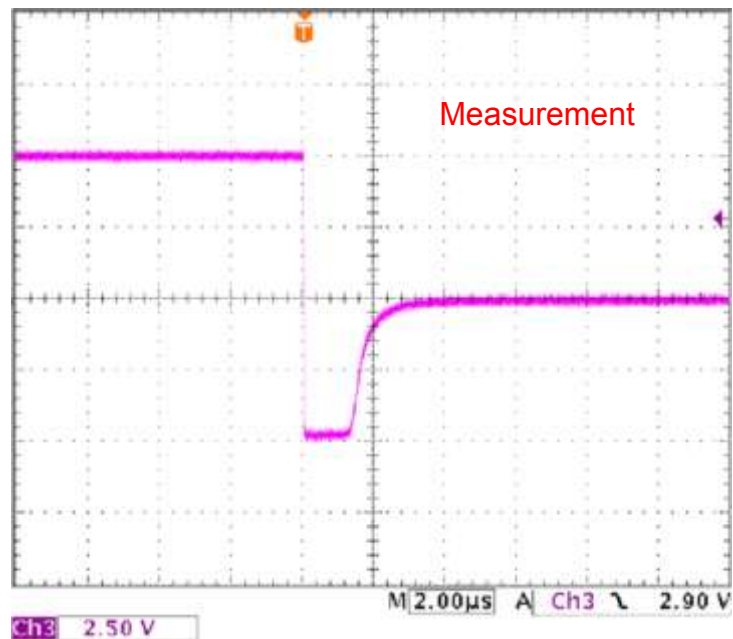


Compare Measurement vs. Simulation

		Measurement	Simulation	Error (%)
trj	us	0.600	0.599	-0.24
trb	us	0.640	0.644	0.55
trr	us	1.240	1.242	0.17

Reverse Recovery Characteristic

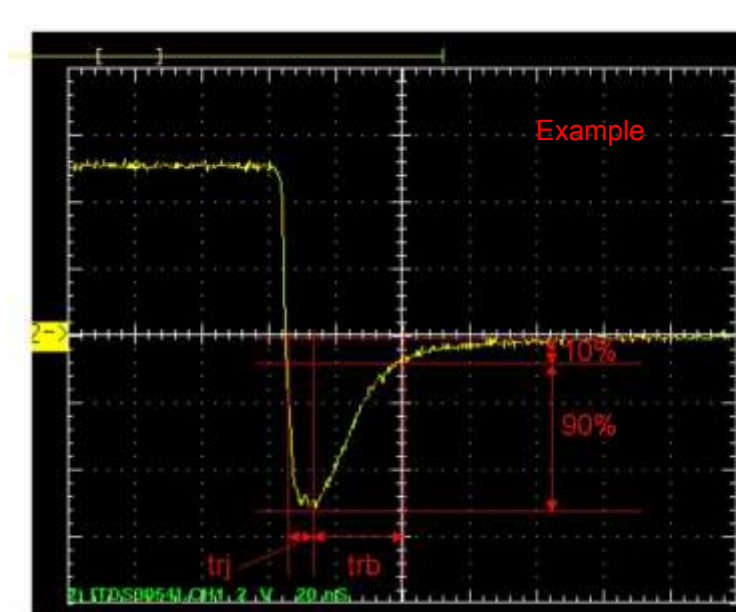
Reference



$T_{rj}=0.60(\mu s)$

$T_{rb}=0.64(\mu s)$

Conditions: $I_{fwd}=I_{rev}=0.2(A)$, $R_l=50$



Relation between t_{rj} and t_{rb}